

ABSTRACT

A probe (20) has a contact portion (20C) at one end and a terminal portion (20T) to contact with a circuit board at another end, and includes: a low-high resistance portion (20LH) formed such that a low-resistance portion (20L) made of a first metal is coated with a high-resistance portion (20H) made of a second metal and has a higher resistivity than the low-resistance portion (20L); and a middle-high resistance portion (20MH) including a middle-resistance portion (20M) which is connected to the low-resistance portion (20L) in a longitudinal direction (X) of the probe (20) and which is made of a third metal having a lower resistivity than the high-resistance portion (20H) and having a higher resistivity than the low-resistance portion (20L), and high-resistance portions (20H) provided on both side surfaces in one direction of the middle-resistance portion (20M), and connected to the high-resistance portion (20H) of the low-high resistance portion (20LH).